


<b>Search Notes</b> 	<b>Application/Control No.</b> 10662490	<b>Applicant(s)/Patent Under Reexamination</b> BAAN, JACOB DE
	<b>Examiner</b> Ajay Vasudeva	<b>Art Unit</b> 3617

SEARCHED			
Class	Subclass	Date	Examiner
All	Updated	2/15/2008	AV
114	230.1		
	230.15--230.19		
	293		

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner